

CERTIFICATE



This is to certify that

Tera Probe, Inc.

Head Office, Development Center

KAKIYA Bldg., 2-7-17 Shin-Yokohama, Kohoku-ku, Yokohama-shi,
Kanagawa-ken 222-0033 Japan

with the organizational units/sites as listed in the annex

has implemented and maintains a **Quality Management System**.

Scope:
Management of Activity

Corporate Scope:
Test service of semiconductor device
Development of test design

Through an audit, documented in a report, it was verified that the management system fulfills the requirements of the following standard:

ISO 9001 : 2008

Certificate registration no.	497904 QM08
Date of original certification	2014-03-26
Date of revision	2017-03-23
Date of certification	2017-03-23
Valid until	2018-09-14



DQS Inc.

Brad McGuire
Managing Director

Accredited Body: DQS Inc., 1130 West Lake Cook Road, Suite 340, Buffalo Grove, IL 60089 USA
Administrative Office: DQS Japan Inc., Shiba-Daimon Excellent Bldg 9F. 2-6-6 Shiba-Daimon, Minatoku,
Tokyo 105-0012 Japan





Annex to certificate
Registration No. 497904 QM08

Tera Probe, Inc.

Head Office, Development Center

KAKIYA Bldg., 2-7-17 Shin-Yokohama, Kohoku-ku, Yokohama-shi,
Kanagawa-ken 222-0033 Japan



Location

Scope

497906

Tera Probe, Inc.
Kyushu Operation Center
1580-1 Yunoura, Ashikita-machi,
Ashikita-gun, Kumamoto-ken 869-5563
Japan

Test service of semiconductor device
Development of test design

497905

Tera Probe, Inc.
Hiroshima Operation Center
7-10 Yoshikawa Industrial Park,
Higashi-Hiroshima-shi,
Hiroshima-ken 739-0153 Japan

Test service of semiconductor device
Development of test design

50300608

Tera Probe, Inc.
System Solution Center
Second Kaida BLDG., 2-17 Sakuramachi,
Chuo-ku, Kumamoto-shi, Kumamoto-ken
860-0805 Japan

Service of Information solution and
communications
Development of hardware and software